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product release

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-	9	("6021437" "6070185" "6085178" "6182136" "6199099" "6202199" "6282701" "6286047" "6192354").pn.	USPAT	2004/04/20 09:47
-	4	(intelligent adj agent\$1) and (("6021437" "6070185" "6085178" "6182136" "6199099" "6202199" "6282701" "6286047" "6192354").pn.)	USPAT	2004/04/20 09:49
-	0	(distribut\$4 adj control\$4) and (("6021437" "6070185" "6085178" "6182136" "6199099" "6202199" "6282701" "6286047" "6192354").pn.)	USPAT	2004/04/20 09:48
-	2	(neural adj network\$1) and (("6021437" "6070185" "6085178" "6182136" "6199099" "6202199" "6282701" "6286047" "6192354").pn.)	USPAT	2004/04/20 09:49
-	1	(fuzzy adj logic) and (("6021437" "6070185" "6085178" "6182136" "6199099" "6202199" "6282701" "6286047" "6192354").pn.)	USPAT	2004/04/20 09:49
-	1	(pattern\$1 adj match\$3) and (("6021437" "6070185" "6085178" "6182136" "6199099" "6202199" "6282701" "6286047" "6192354").pn.)	USPAT	2004/04/20 09:49
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